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## XRF-WIE2

Glass monitor standard (SUS setting up standard) for XRF-spectrometers

Approximate composition in mass %

SiO <sub>2</sub>	38.9
B <sub>2</sub> O <sub>3</sub>	5
Na <sub>2</sub> O	14
MgO	1.66
Al <sub>2</sub> O <sub>3</sub>	1.89
P <sub>2</sub> O <sub>5</sub>	1.15
SO <sub>3</sub>	1.25
K <sub>2</sub> O	5.00
CaO	3
TiO <sub>2</sub>	0.83
Cr <sub>2</sub> O <sub>3</sub>	1.46
MnO <sub>2</sub>	3.16
Fe <sub>2</sub> O <sub>3</sub>	2.86
CoO	1.27
NiO	2.55
CuO	2.5
ZnO	2.49
As <sub>2</sub> O <sub>3</sub>	0.66
Se	0.5
ZrO <sub>2</sub>	0.68
Ag <sub>2</sub> O	0.54
CdO	0.57
SnO	2.27
Sb <sub>2</sub> O <sub>3</sub>	0.6
Te	0.5
BaO	2
PbO	2.15
Bi <sub>2</sub> O <sub>3</sub>	0.56

The concentrations of all elements were calculated from the composition of the glass melt.

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